



Trace Contaminant Detection by Ultraviolet Microscopy and Microspectroscopy

Detection and analysis of trace organic and inorganic contaminants on precision devices by ultraviolet microscopy and microspectroscopy.

San Dimas, CA, May 23, 2008 --(PR.com)-- Organic and inorganic contaminants of precision devices such as flat panel displays, MEMS device and patterned semiconductors are often difficult to detect. Many contaminant materials are essentially invisible to common analytical techniques such as optical microscopy. CRAIC Technologies, Inc, a global leader in application-focused microanalysis solutions, provides the capability to both detect and analyze trace contaminants with a single instrument. This is done by combining both ultraviolet microscopy with ultraviolet microspectroscopy in the CRAIC Technologies QDI 2010™ microspectrophotometer equipped with the optional QDI ImageUV™ package.

Many organic and inorganic materials absorb light in the ultraviolet region but are invisible to the naked eye. This means that standard optical microscopy will not be able to detect these contaminants and has no other means of analyzing them. While other techniques are available, they require extensive sample preparation and can damage the sample. By utilizing ultraviolet micro-imaging, the user is able to quickly, easily and non-destructively locate many contaminants. UV microspectroscopy can then be performed to measure the electronic spectral characteristics of the contaminant in order to identify it. The spectra can also be used to further improve the clarity of the image of the contaminants by determining the wavelength of maximum absorbance. By combining both techniques in a single instrument, the QDI 2010™ microspectrophotometer, the user is easily able to locate and identify contaminant materials on flat panel displays, semiconductor chips, MEMS and even microfluidic devices. The QDI 2010™ microspectrophotometer is the first system ever to combine both UV microscopy and microspectroscopy in a single tool. It can also be upgraded to enable ultraviolet, visible and near infrared reflectance, transmittance and fluorescence microscopy and microspectroscopy.

For more information about the QDI 2010™ Microspectrophotometer and contamination detection by UV microscopy, visit www.microspectra.com.

About CRAIC Technologies: CRAIC Technologies, Inc. is a global technology leader focused micro imaging and microspectroscopy in the ultraviolet, visible and near-infrared regions. CRAIC Technologies creates innovative solutions, with the very best in customer support, by listening to thier customers and implementing solutions that integrate operational excellence and technology expertise. CRAIC Technologies provides solutions for customers in forensic sciences, health sciences, semiconductor, geology, nanotechnology and materials science markets whose applications demand accuracy, precision, speed and the best in customer support.

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